

**Search Notes**

Application/Control No.

10/725,029

Examiner

Devin Hanan

Applicant(s)/Patent under  
Reexamination

MEIER ET AL.

Art Unit

3745

**SEARCHED**

Class	Subclass	Date	Examiner
415	110,134		
	168.2		
	174.3		
	177,178	10/30/2006	DH

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR